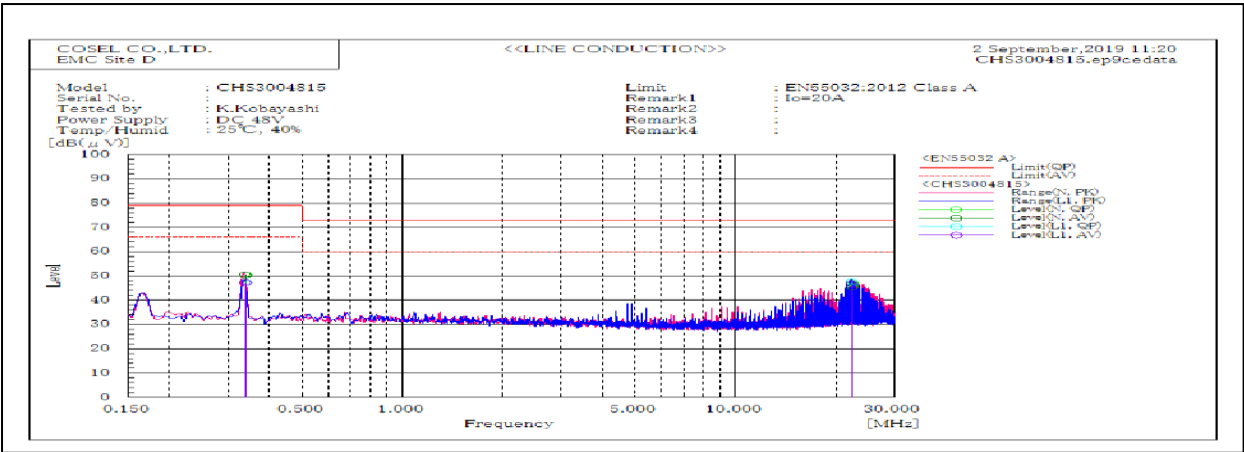
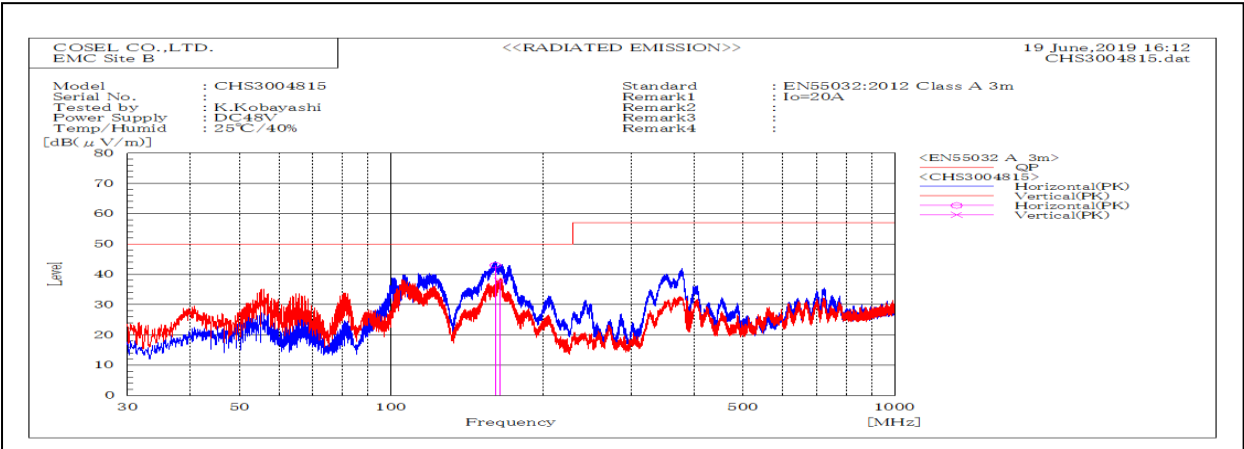


DATA SHEET		Date	02-Sep-19
Model	CHS3004815	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Kobayashi



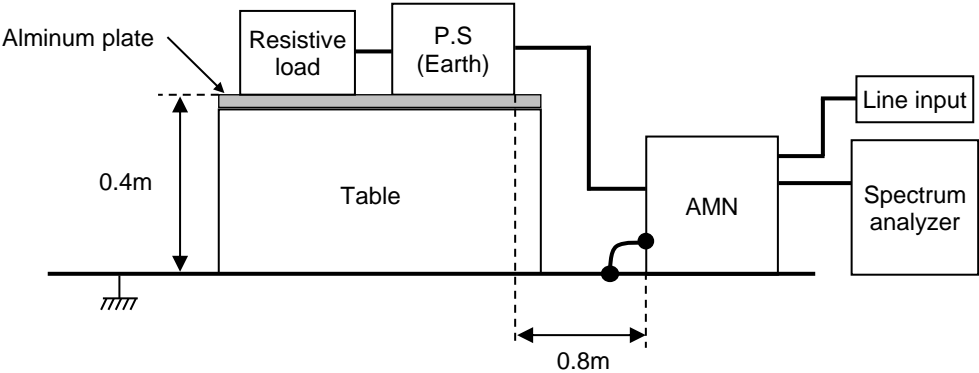
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.34	L1	47.4	47.3	79.0	66.0	31.6	18.7	Pass	
22.32	L1	47.5	46.7	73.0	60.0	25.5	13.3	Pass	
0.34	N	50.5	50.5	79.0	66.0	28.5	15.5	Pass	
22.49	N	46.9	45.5	73.0	60.0	26.1	14.5	Pass	



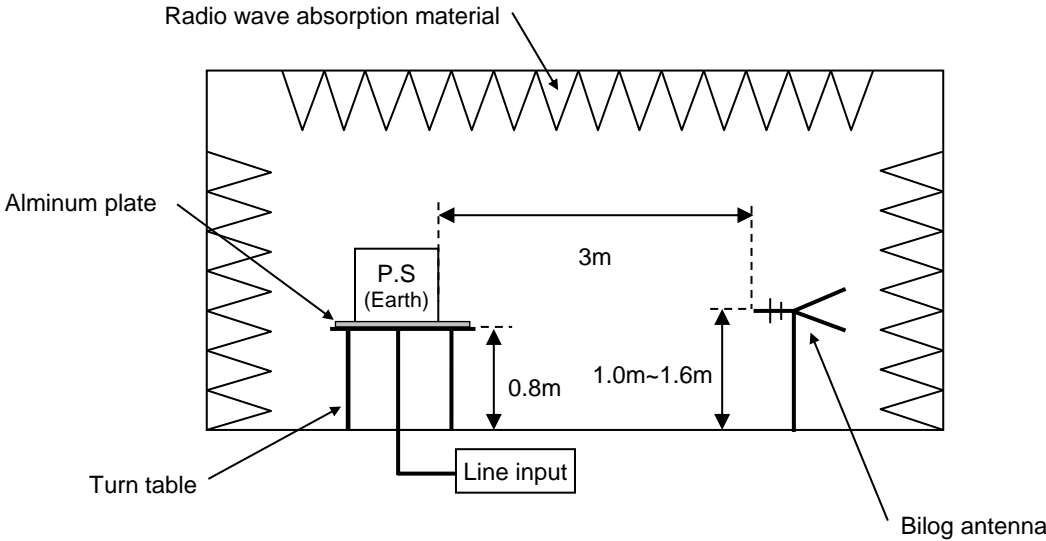
Frequency MHz	Polarization	Stability	Level dB(μV/m)	Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
161.07	H	Stable	43.0	50.0	7.0	Pass	194.5	62.4	
164.87	V	Stable	37.8	50.0	12.2	Pass	200.0	184.9	

DATA SHEET		Date	02-Sep-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Kobayashi

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name : CHS30048□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

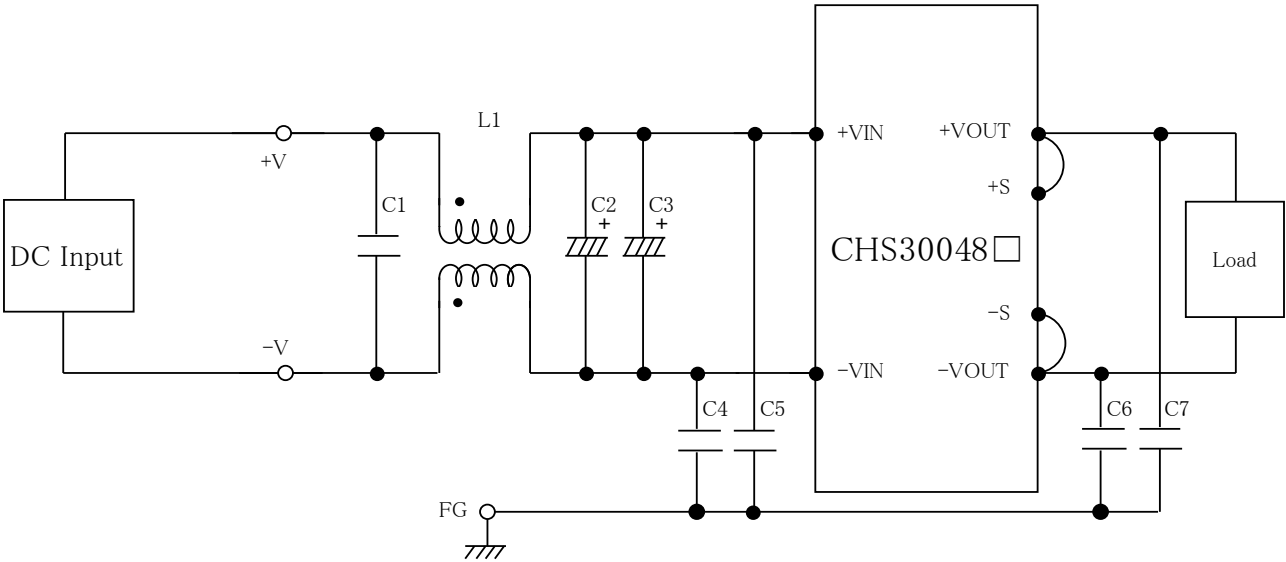


Fig.1 Testing circuitry

- L1 : 1mH SC-20-10JH (TOKIN)
- C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
- C2,C3 : 100V 100 μ F PWseries (nichicon)
- C4,C5 : 630V 0.068 μ F FPD22J683J4(NITSUKO)
- C6,C7 : 630V 0.033 μ F FPD22J333J4(NITSUKO)